



University of Essex

Department of
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Engineering** 

Electron transport in dilute nitrides

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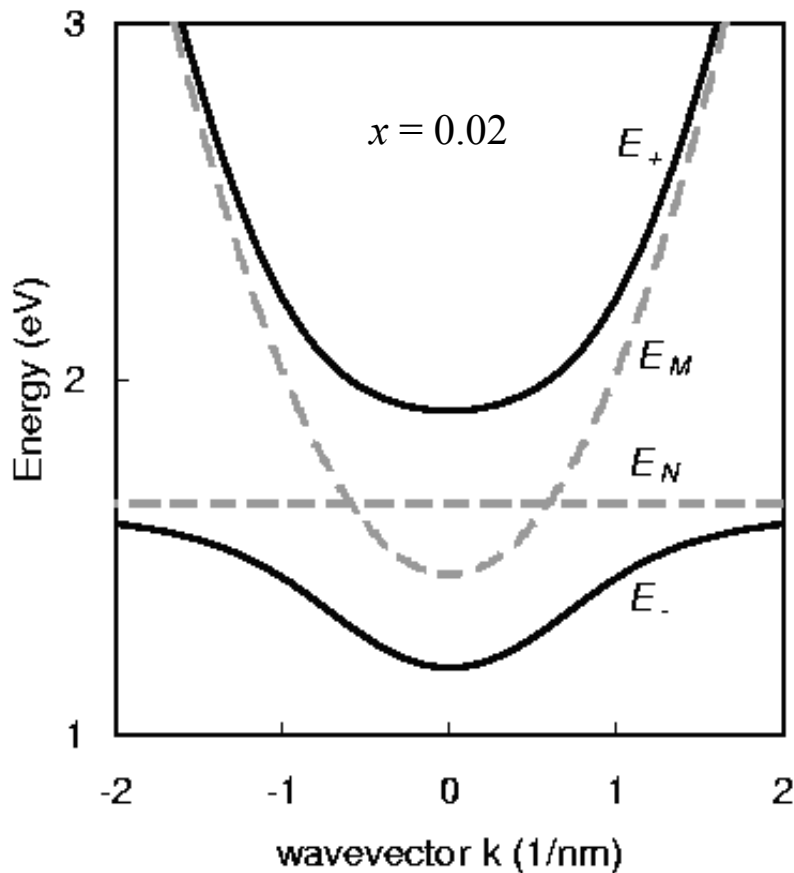
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Overview

- Effects of non-parabolicity
 - Problem with the density of states
 - Observed mobilities
 - Models of alloy / nitrogen scattering
 - Solution of the Boltzmann equation
 - The 'ladder method'
 - Calculations
 - Conclusions
-

Non-parabolicity

Band anticrossing (BAC) model¹



- Effective mass
- Density of states
- Group velocity

[1] W. Shan et al, *Phys. Rev. Lett.*, **82**, 1221, (1999)

General formula for dispersion relations

The dispersion relations can be written in the form:

$$\frac{\hbar^2 k^2}{2m^*} = \gamma(E),$$

where

$$\gamma(E) = \frac{\beta^2 x}{E_N - E} + E - E_c,$$

(From BAC model¹).

[1] W. Shan et al, *Phys. Rev. Lett.*, **82**, 1221, (1999)

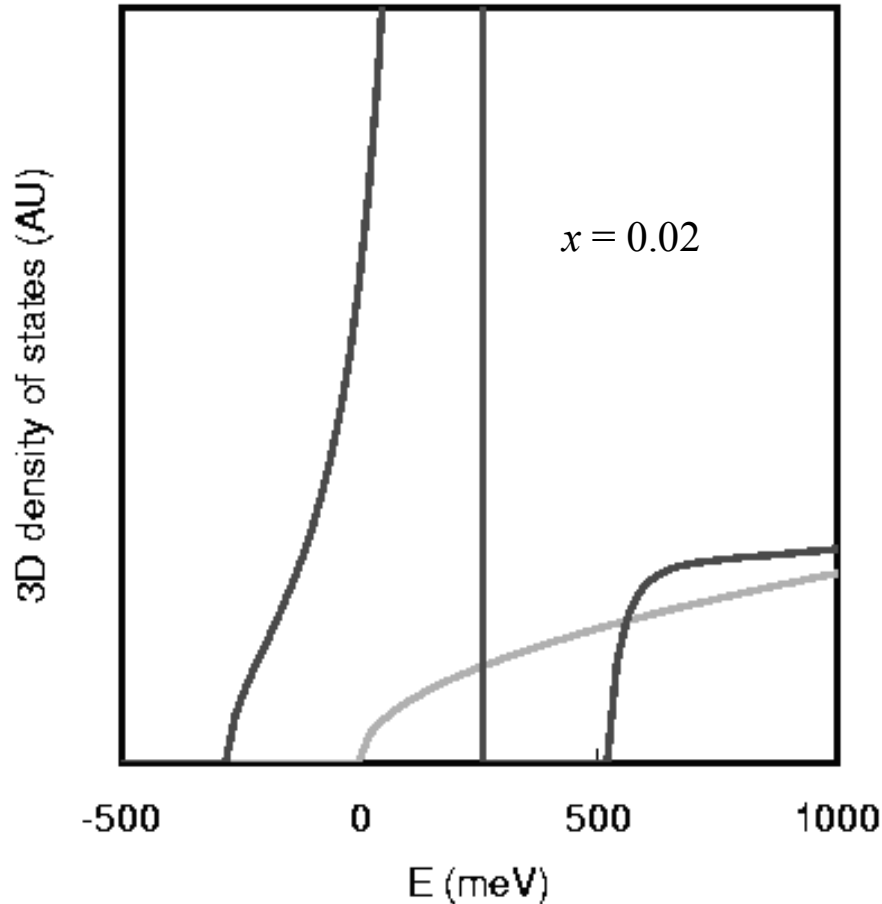
Densities of states (DOS) in non-parabolic bands

$$N_{3D}(E) = \frac{(2m^*)^{3/2}}{4\pi^2 \hbar^3} \gamma^{1/2}(E) \frac{d\gamma(E)}{dE}, \quad \text{3D density of states.}$$

$$N_{2D}(E) = \frac{m^*}{2\pi \hbar^2} \frac{d\gamma(E)}{dE}, \quad \text{2D density of states.}$$

However...

The density of states



- Becomes infinite at E_N
- Predicts infinite number of states below E_N

The Green's function approach

Wu *et al*¹ find Green's function from Anderson many-impurity model²

$$G(E, E_M) = \left\{ E - E_M - \frac{\beta^2 x}{E - E_N + i\Delta} \right\}^{-1}.$$

Density of states is then

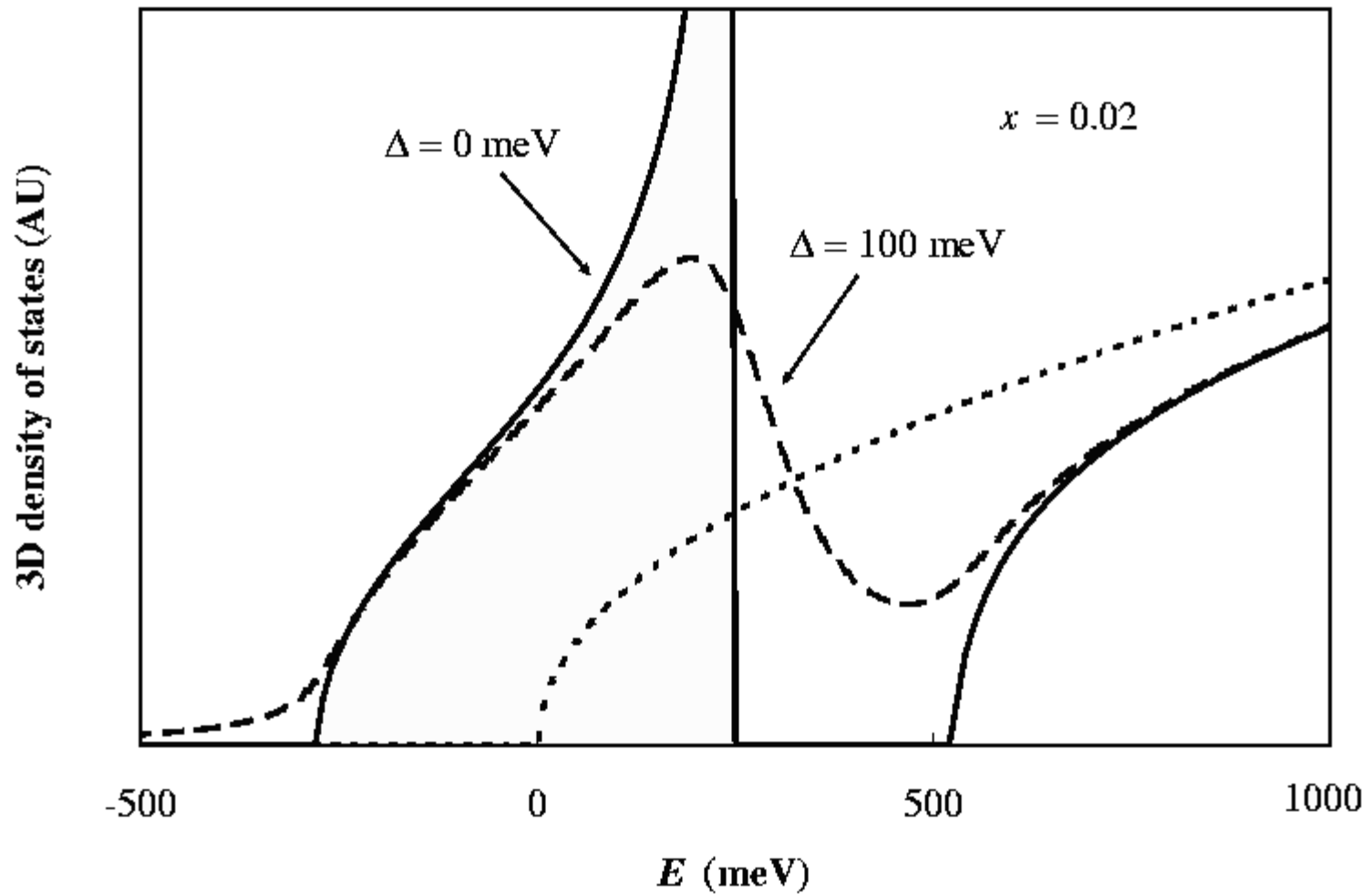
$$N(E) = -\frac{1}{\pi} \text{Im} \int G(E, E_M) N_0(E_M) dE_M.$$

where N_0 is the DOS in matrix semiconductor.

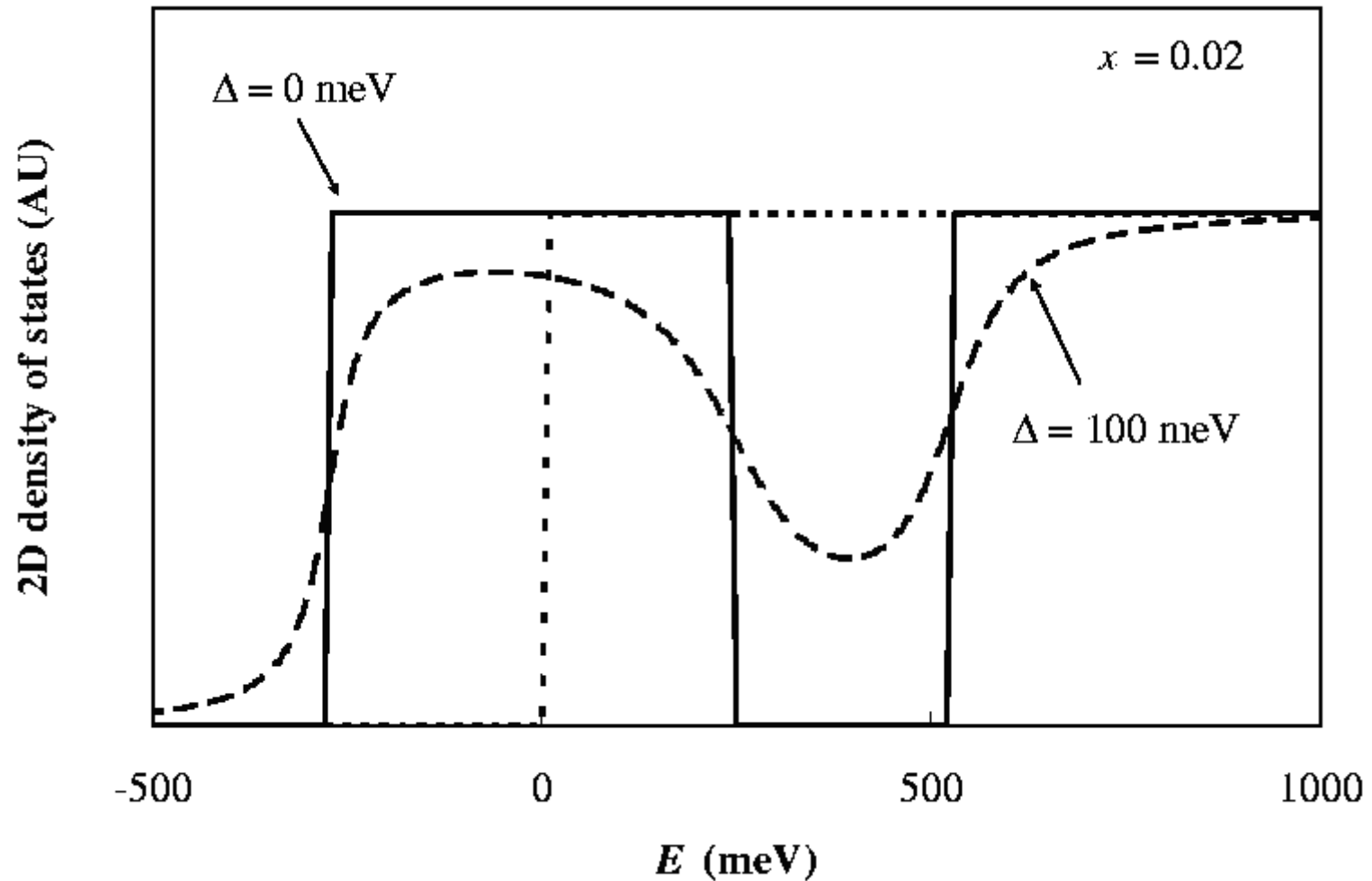
[1] J. Wu, et al, *Phys. Rev. B*, **65**, 233210, (2002)

[2] P.W. Anderson, *Phys. Rev.*, **124**, 41, (1961)

The 3D density of states



The 2D density of states



The energy broadening Δ

Finite Δ

- interpreted as an energy broadening

$\Delta \rightarrow 0$

- factor of $d\gamma(E)/dE$ disappears from densities of states
- Predicts finite number of states below E_N

$\Delta \rightarrow \infty$

- densities of states approach those of the matrix semiconductor
 - real part of dispersion relations become those of the matrix semiconductor
-

Densities of states for $\Delta \rightarrow 0$

$$N_{3D}(E) = \frac{(2m^*)^{3/2}}{4\pi^2 \hbar^3} \gamma^{1/2}(E), \quad \text{3D density of states.}$$

$$N_{2D}(E) = \frac{m^*}{2\pi \hbar^2}, \quad \text{2D density of states (within the band)}$$

(m^* is the effective mass of the *matrix* semiconductor).

i.e. these are the same as before except that the factor of $d\gamma(E)/dE$ has disappeared.

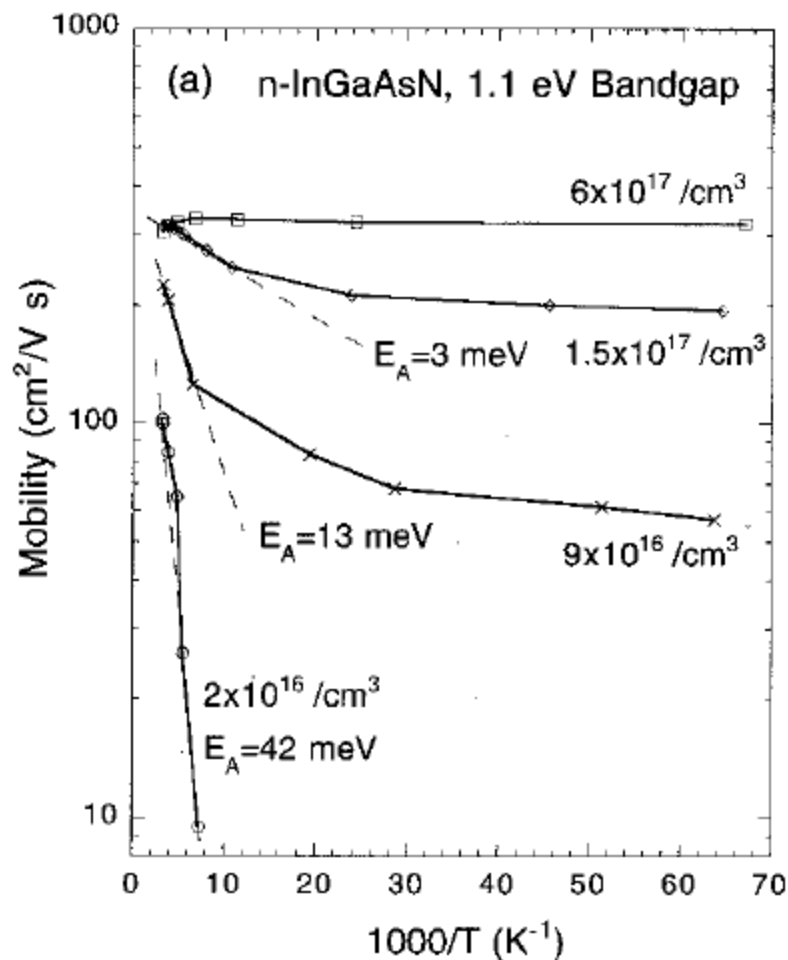
Consequences for scattering rates and relaxation times

$$W(E) = \frac{1}{\tau(E)} = \frac{2\pi}{\square} |M(E)|^2 N(E),$$

Assuming $M(E)$ is slowly varying:

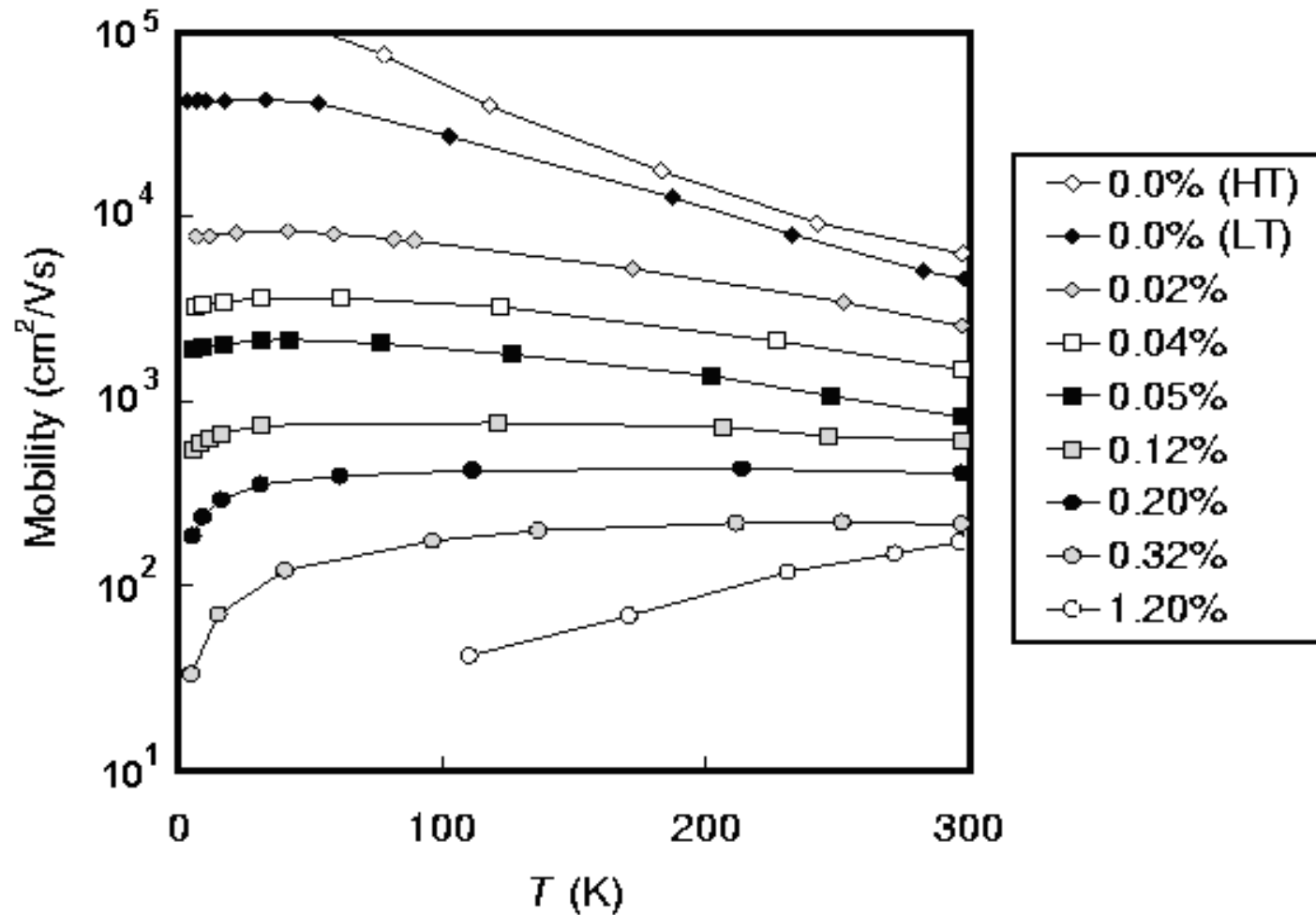
- $\tau(E) \rightarrow 0$ as $E \rightarrow E_N$ in 3D case but not in 2D case for modified DOS
 - $\tau(E) \rightarrow 0$ as $E \rightarrow E_N$ in both cases for usual DOS in non-parabolic band
 - Immobility of N state manifests through group velocity.
-

Observed mobilities - GaInNAs 2% N (Kurtz et al¹)



- Thermally activated mobility
- Activation energy decreases with increasing electron concentration
- Low T mobility still large for hopping conductivity

Observed mobilities - GaNAs/AlGas heterostructures (Mouillet et al¹)



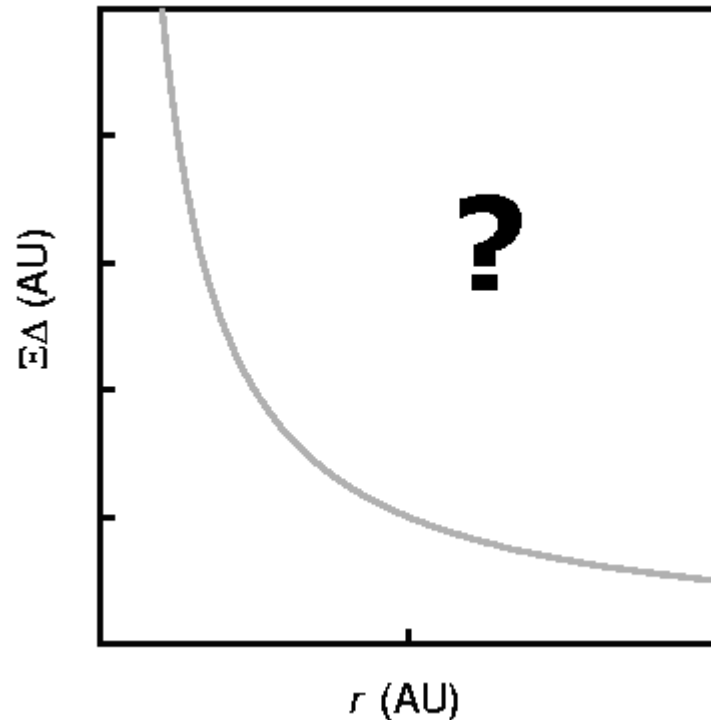
Alloy scattering – the microscopic approach¹

- Alloy treated in the virtual crystal approximation
- Scattering due to fluctuations ΔV around average potential
- Nature of ΔV ?
 - Band-edge difference
 - Electron affinity difference
 - Electro-negativity difference
 - Dielectric approach² (used to explain optical bowing in alloys)

[1] J.W. Harrison and J.R. Hauser, *Phys. Rev. B*, **13**, 5347 (1976)

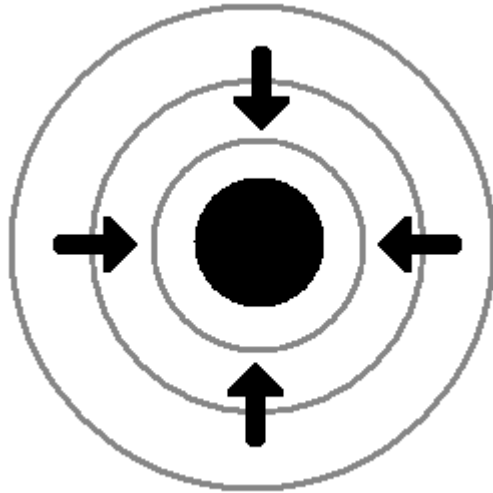
[2] J.A. Van Vechten and T.K. Bergstresser, *Phys. Rev. B*, **1**, 3351 (1970)

Strain scattering?



- Strain shifts band-edge – related via deformation potential Ξ
- In Γ valley energy change is through pure dilation Δ
- Looking for an r dependent dilation that could yield a scattering cross-section

Trial model



- Consider isolated impurity
- Assume matrix material is isotropic
- Use linear theory of elasticity in spherical polar coordinates

But...

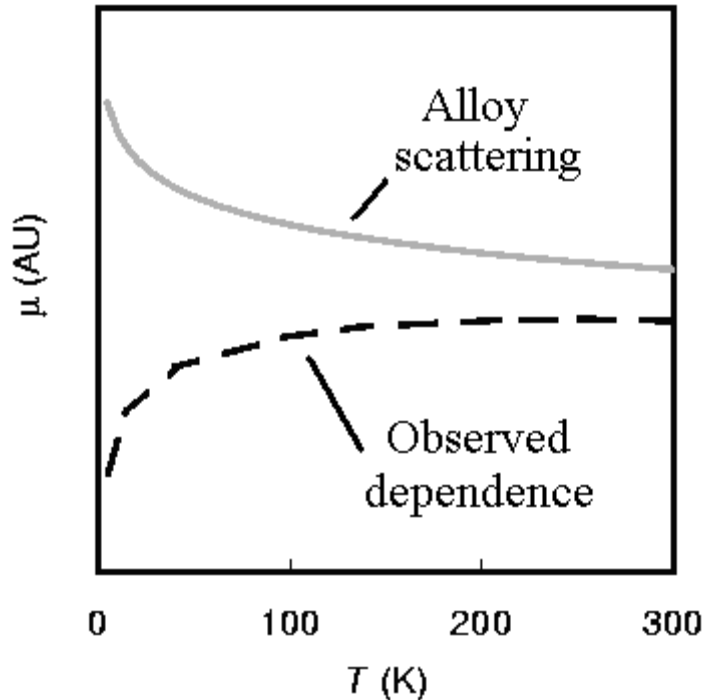
In spherical polar coordinates, without a body force the dilation is a constant (taken to be due to external pressure) – no effect!

Alloy scattering – the phenomenological approach

- Scattering related to variation of band-edge with alloying
- Large bowing in dilute nitrides
 - Hellman-Feynman theorem¹
 - S-matrix theory²

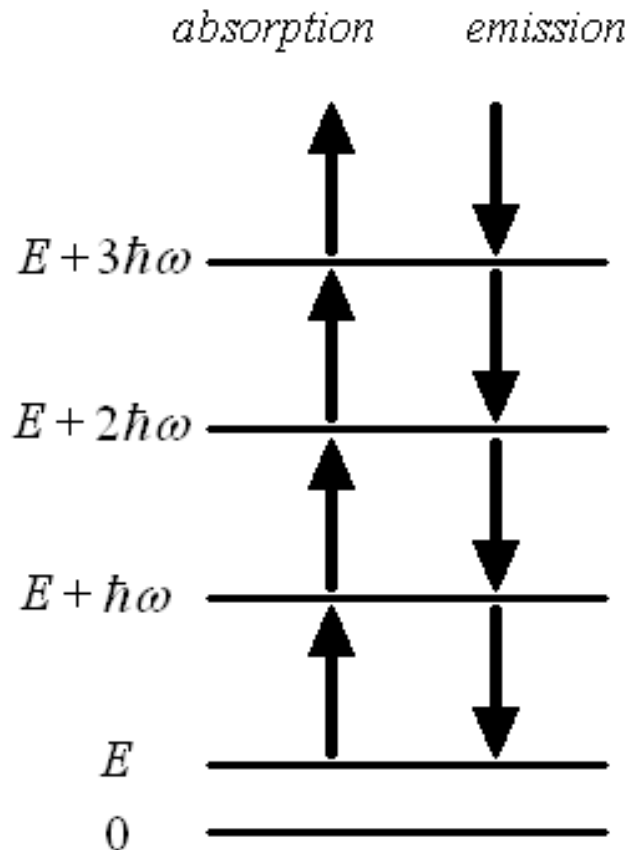
[1] M. Auslender and S. Hava, *Solid State Commun.*, **87**, 335 (1993)
[2] S. Fahy and E.P. O'Reilly, *Appl. Phys. Lett.*, **83**, 3731 (2003)

Alloy scattering – temperature dependence



- All models predict a mobility that varies as $T^{-1/2}$
- Observed mobilities show increasing T dependence at low T
- Low T mobility possibly due to defects

Polar optical phonons – the ladder method^{1,2}

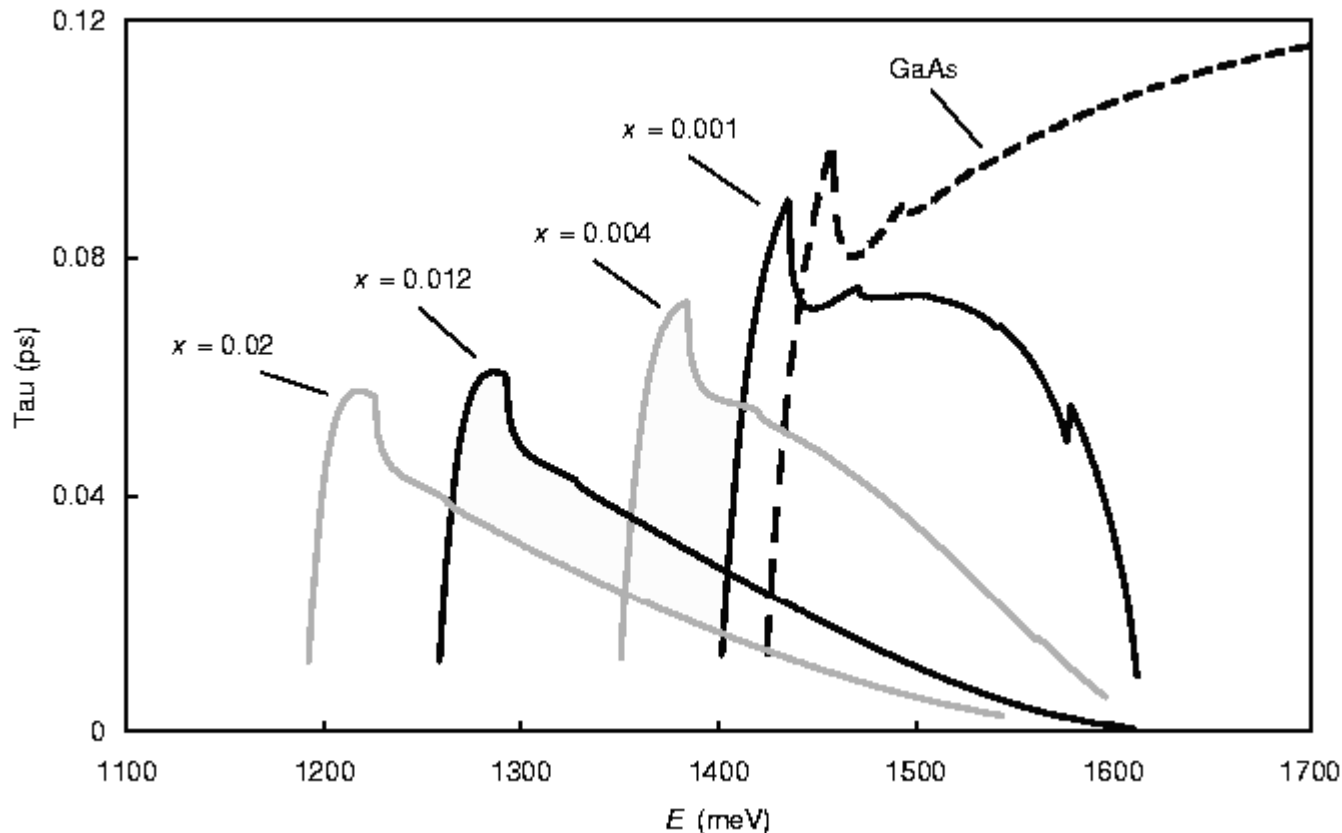


- Inelastic process
- Scattering rate at E related to rates at $E \pm \hbar\omega$
- No unique relaxation time

[1] R.T. Delves, *Proc. Phys. Soc.*, **73**, 572 (1959)

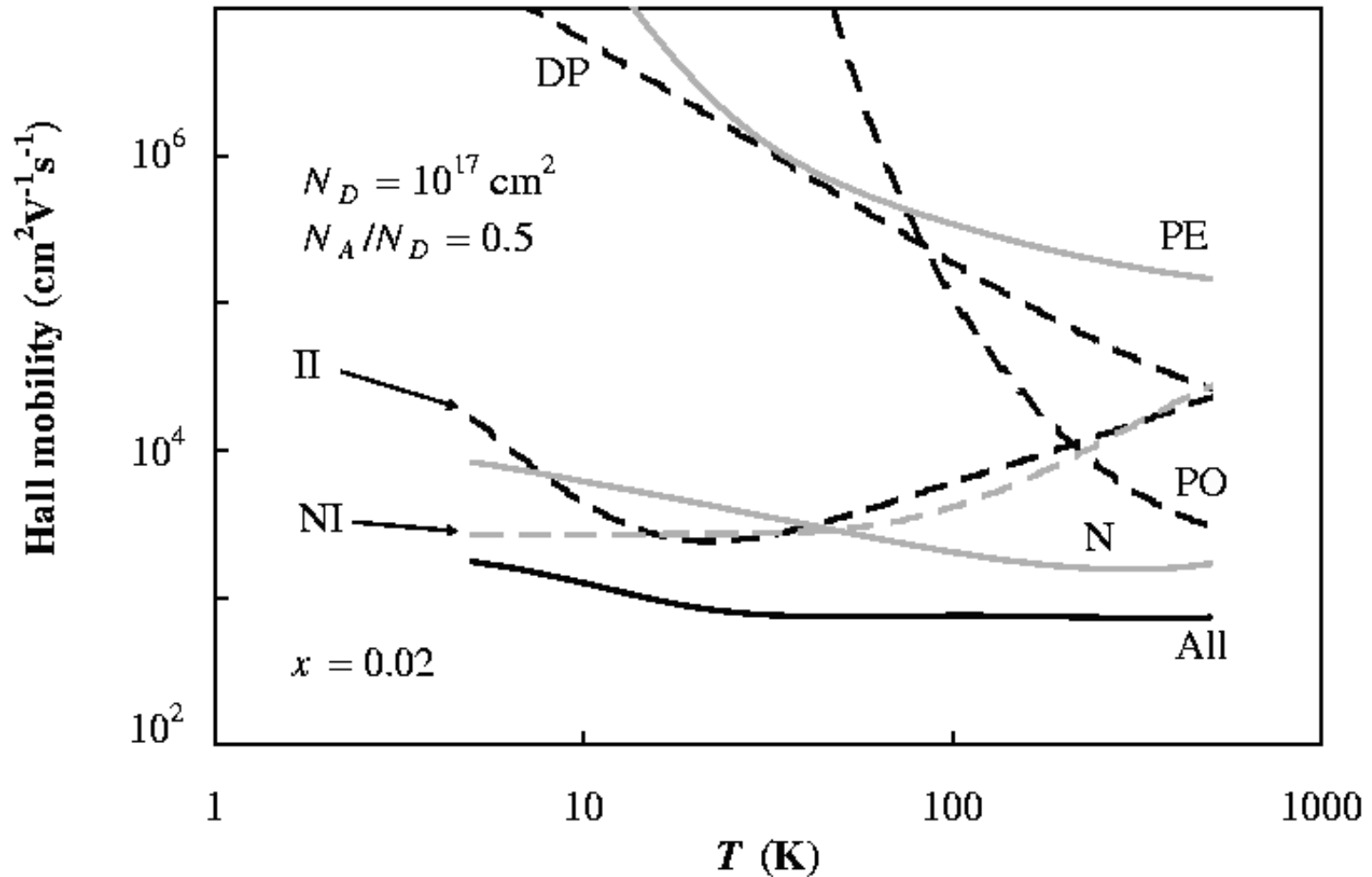
[2] K. Fletcher and P.N. Butcher, *J. Phys. C: Solid State Phys.*, **5**, 212 (1972)

Calculated relaxation times for non-parabolic bands¹



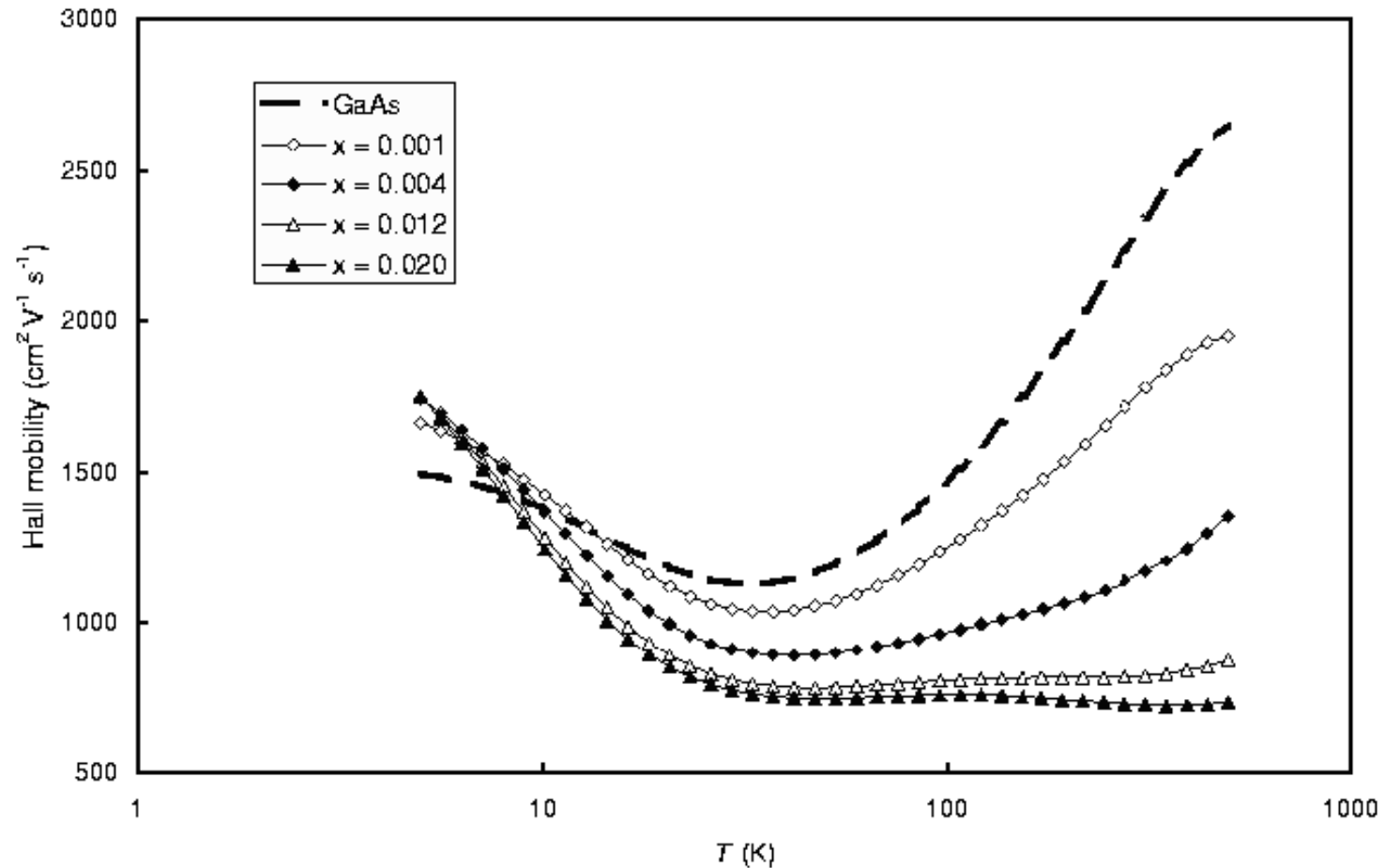
- $T = 300$ K
- Bulk GaNAs
- Normal non-parabolic DOS

Calculated mobilities¹ – all processes

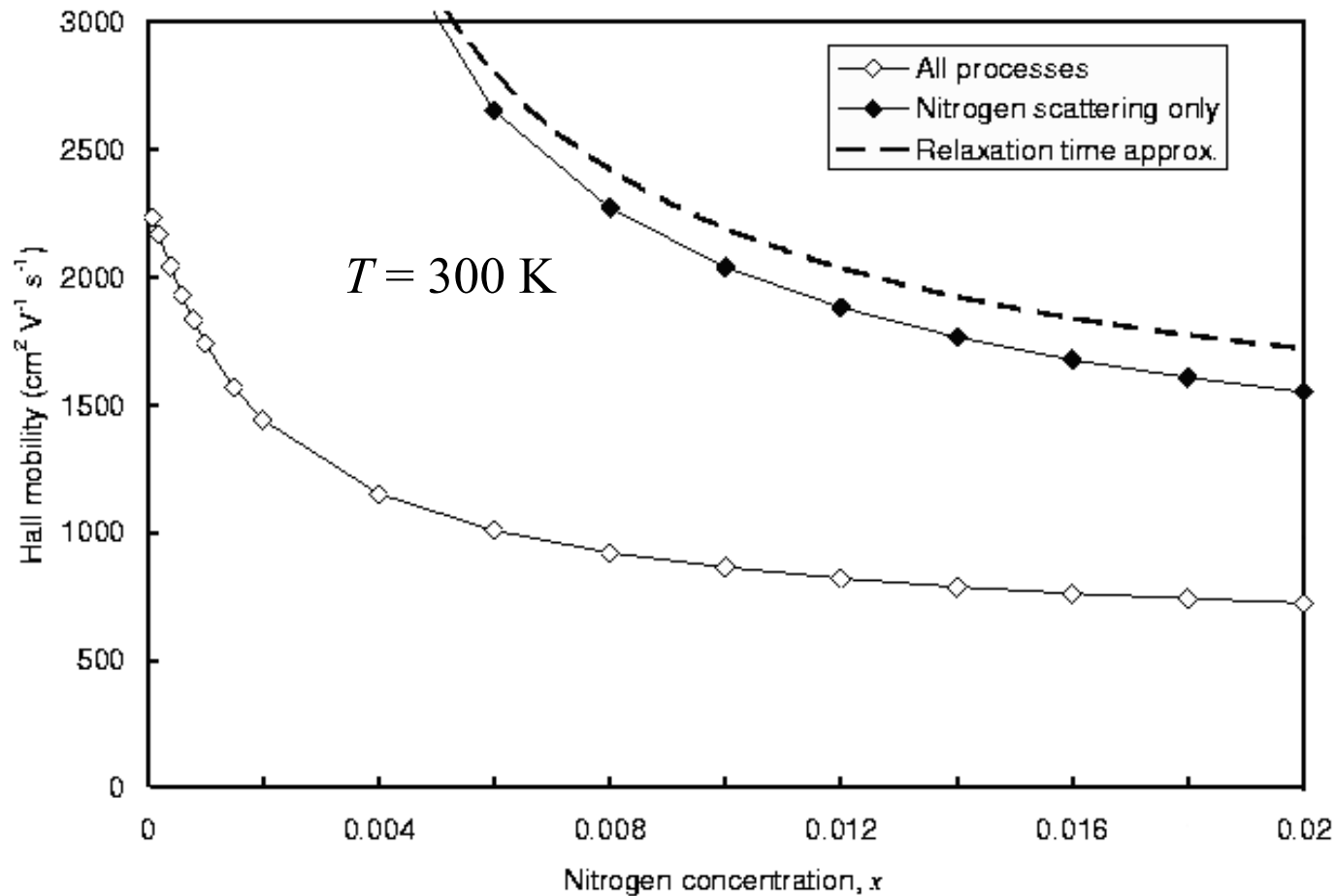


[1] M.P. Vaughan and B.K. Ridley, *Phys. Rev. B*, **72**, 075211 (2005)

Calculated mobilities¹ – T dependence



Calculated mobilities¹ – x dependence



Conclusions

- High temperature mobility limited by nitrogen scattering
 - Polar optical phonon scattering still important at high temperature
 - Alloy scattering does not model low temperature mobility
 - Low temperature mobility likely to be limited by defects / trapping centres
 - For high field, effect of DOS may be significant for hot electrons
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Thank you
for your attention



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